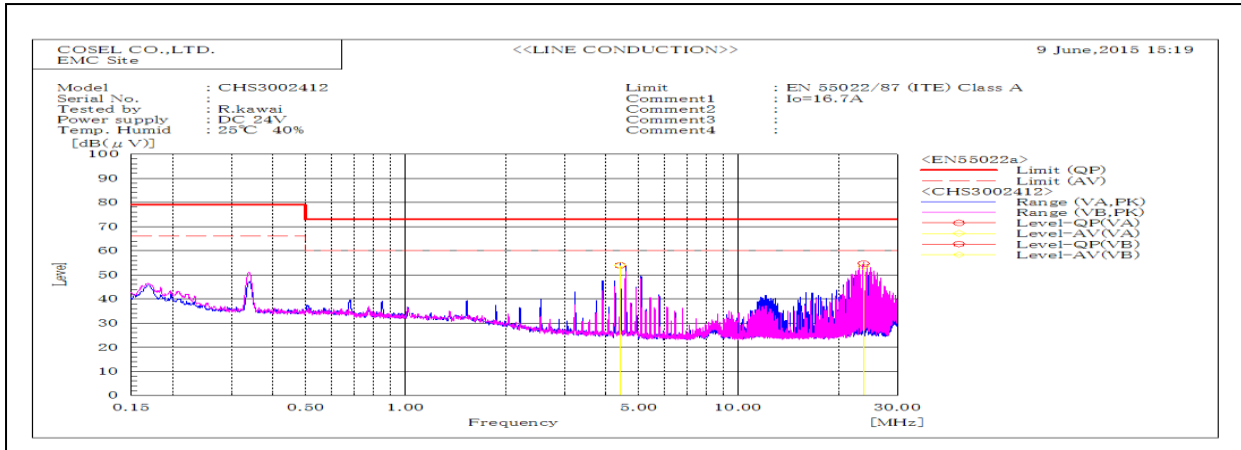
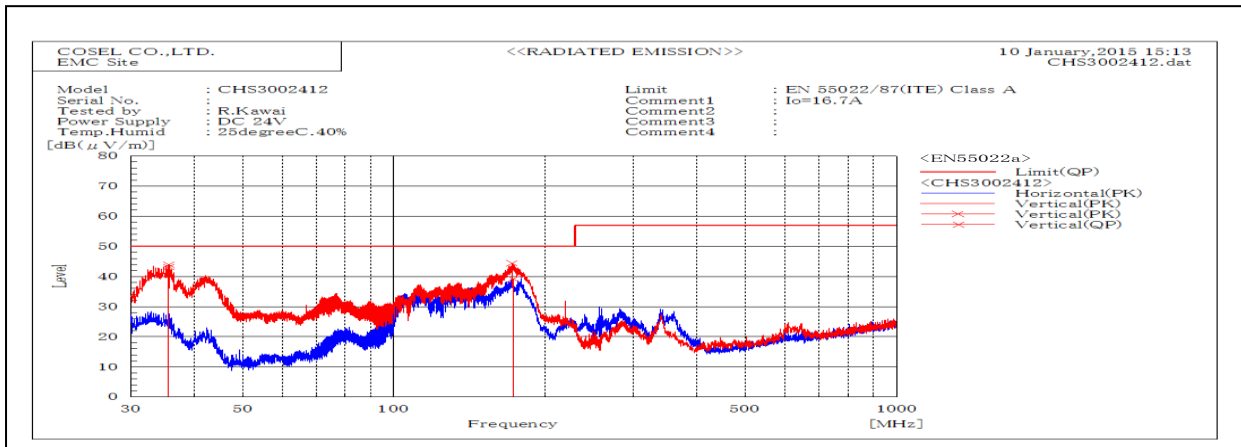


DATA SHEET		Date	10-Jun-15
Model	CHS3002412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



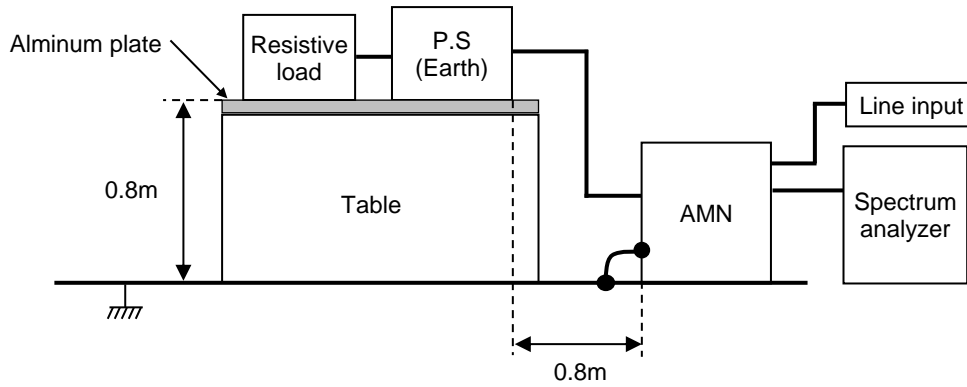
Frequency MHz	Ham	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
4.41082		VA	33.7	33.8	20.2	53.9	54	73	60	19.1	6	Pass	
23.7608		VB	33.8	32.5	20.9	54.7	53.4	73	60	18.3	6.6	Pass	



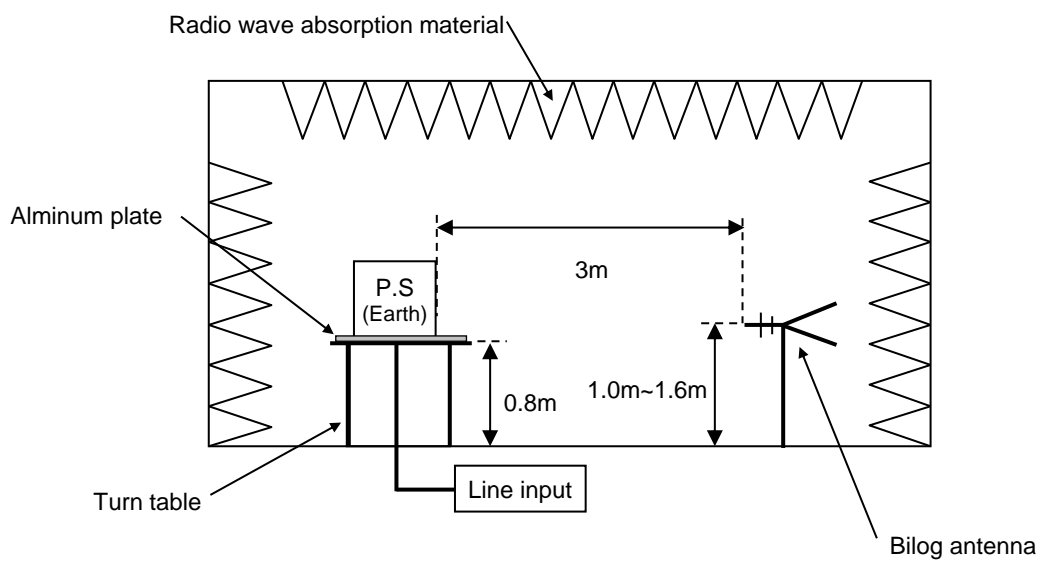
Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
35.638	V	Stable	58.1	-14.9	43.2	50	6.8	Pass	101	224	
172.578	V	Stable	55.3	-16.1	39.2	50	10.8	Pass	128	340	

DATA SHEET		Date	10-Jun-15
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

## 1. Line conduction



## 2. Radiated emission



## Conditions

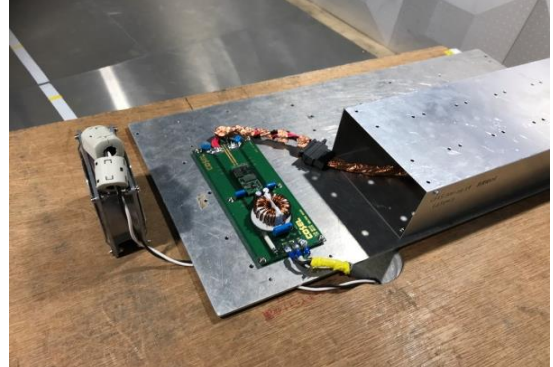
Test : EMI  
 Model Name : CHS30024□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

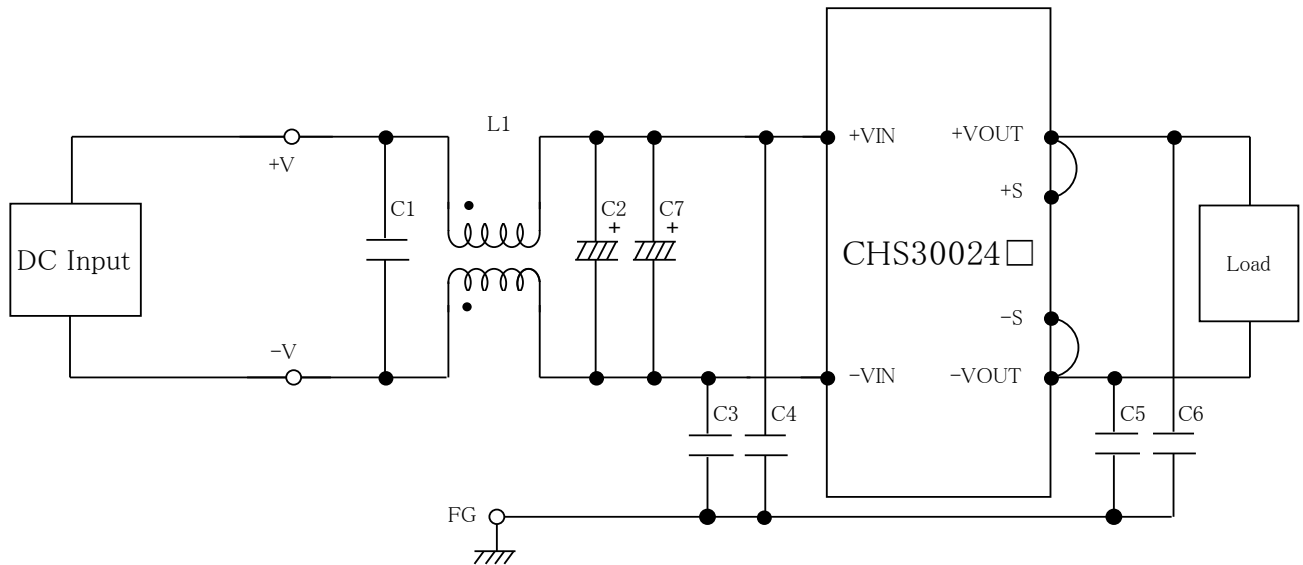


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2  $\mu$ F FPD22E225J4 (NITSUKO)
- C2,C7 : 50V 330  $\mu$ F PWseries (nichicon)
- C3,C4 : 630V 0.068  $\mu$ F FPD22J683J4(NITSUKO)
- C5,C6 : 630V 0.033  $\mu$ F FPD22J333J4(NITSUKO)